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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

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NFORMATION DISCLOSURE STATEMENT BY APPLICANT

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APPLICANT: Maurice Lee Smith et al.

FILING DATE: 9/26/2003

GROUP:

1631 2878

U.S. PATENT DOCUMENTS

EXAM. INITIAL		DOCUMENT NUMBER				DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE			
,		6	6	2	8	9	4	1	9/30/03	Knoblach et al.	<u> </u>		
l		6	6	0	8	5	5	9	8/19/03	Lemelson et al.			
1		6	5	8	8	7	0	1	7/08/03	Yavnal			
ı		6	4	9	8	0	4	1	12/24/02	Tabacco et al.	,	-	
1		6	4	9	0	5	3	0	12/03/02	Wyatt			
1		6	4	4	6	0	0	4	9/03/02	Cao et al.			
1		6	3	5	6	6	2	5	3/12/02	Castellani et al.			
î		6	3	2	7	5	3	5	12/04/01	Evans et al.			
١		6	3	1	7	0	8	0	11/13/01	Baxter, Jr.			
ı		6	1	6	9	4	7	6	01/02/01	Flanagan			
į.		6	0	8	3	2	4	8	7/04/00	Thompson			
1		6	0	7	5	8	9	1	6/13/00	Burman	-		
ı		6	0	5	2	1	8	7	4/18/00	Krishnan et al.			
ł		6	0	2	3	2	2	3	2/08/00	Baxter, Jr.			
١		5	9	7	2	6	3	8	10/26/99	Burlage et al.			
,		5	9	3	8	7	2	1	8/17/99	Dussell et al.	-		
1		5	8	3	8	2	3	7	11/17/98	Revell et al.			
ì		5	6	5	0	8	0	٥	7/22/97	Benson			
1		5	6	4	8	9	1	4	7/15/97	Bauer et al.	-		
		5	5	2	8	2	4	8	6/18/96	Steiner et al.			
,		5	4	7	0	2	3	3	11/28/95	Fruchterman et al.			
1		5	4	4	4	4	4	4	8/22/95	Ross			
,		4	8	6	1	7	2	7	8/29/89	Hauenstein et al.			
1	•			н	1	3	4	4	4/02/94	Baldauf et al.			

FOREIGN PATENT DOCUMENTS

 											
	DOCUM	ENT N	UMBE	R		DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
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	RMATION DISCLOSURE TEMENT BY APPLICANT	APPLICANT: Maurice Lee Smith et al.			
(Use several sheets if necessary)		FILING DATE: 9/26/2003	GROUP: 2878		

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

1	"Oak Ridge claims sensitivity record for Si MEMS sensor"; June 23, 2003 article in Electronic Engineering Times; Author R. Colin Johnson, page 49.

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Exr. Le

Date: 2/06